

**MOTOROLA**

Octal D-Type Positive Edge-Triggered Flip-Flop With 3-State Inverted Outputs

ELECTRICALLY TESTED PER:
MIL-M-38510/34106

The 54F534 is a high-speed, low-power octal D-type flip-flop featuring separate D-type inputs for each flip-flop and 3-state outputs for bus oriented applications. A buffered Clock (CP) and Output Enable (\overline{OE}) are common to all flip-flops. The 'F534 is the same as the 'F374 except that the outputs are inverted.

- Edge-Triggered D-Type Inputs
- Buffered Positive Edge-Triggered Clock
- 3-State Outputs for Bus Oriented Applications

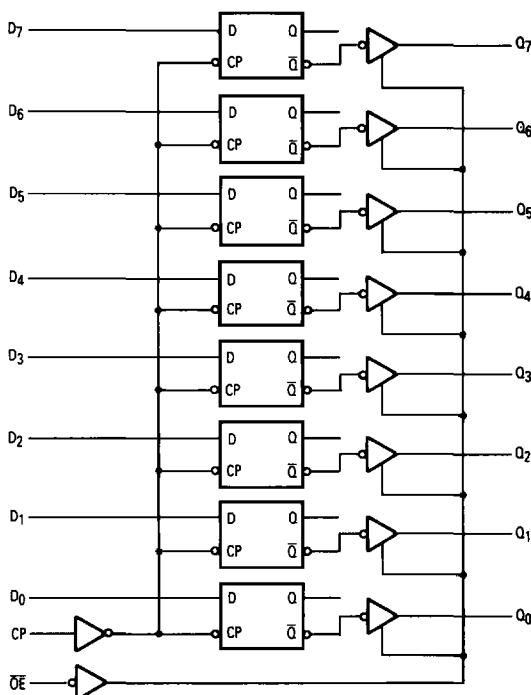
Military 54F534**AVAILABLE AS:**

- 1) JAN: JM38510/34106BXA
- 2) SMD: *
- 3) 883C: 54F534/BXAJC

X = CASE OUTLINE AS FOLLOWS:
PACKAGE: CERDIP: R
CERFLAT: S
LCC: 2

*Call Factory for latest update

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LOGIC DIAGRAM**PIN ASSIGNMENTS**

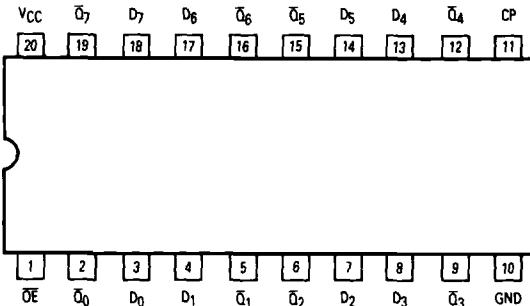
FUNCTION	DIL	FLATS	LCC	BURN-IN (CONDITION A)
\overline{OE}	1	1	1	V _{CC}
\overline{Q}_7	2	2	2	OPEN
\overline{Q}_6	3	3	3	V _{CC}
\overline{Q}_5	4	4	4	V _{CC}
\overline{Q}_4	5	5	5	OPEN
\overline{Q}_3	6	6	6	OPEN
\overline{Q}_2	7	7	7	V _{CC}
\overline{Q}_1	8	8	8	V _{CC}
GND	9	9	9	OPEN
CP	10	10	10	GND
\overline{Q}_0	11	11	11	V _{CC}
\overline{D}_7	12	12	12	OPEN
\overline{D}_6	13	13	13	V _{CC}
\overline{D}_5	14	14	14	V _{CC}
\overline{D}_4	15	15	15	OPEN
\overline{D}_3	16	16	16	OPEN
\overline{D}_2	17	17	17	V _{CC}
\overline{D}_1	18	18	18	V _{CC}
\overline{D}_0	19	19	19	OPEN
\overline{V}_{CC}	20	20	20	V _{CC}

BURN-IN CONDITIONS:
 $V_{CC} = 5.0 \text{ V MIN}/6.0 \text{ V MAX}$

TRUTH TABLE			
Inputs		Outputs	
D _n	CP	OE	Q _n
H		L	H
L		L	L
X	X	H	Z

H = HIGH Voltage Level
L = LOW Voltage Level
X = Immaterial
Z = HIGH Impedance

CONNECTION DIAGRAM



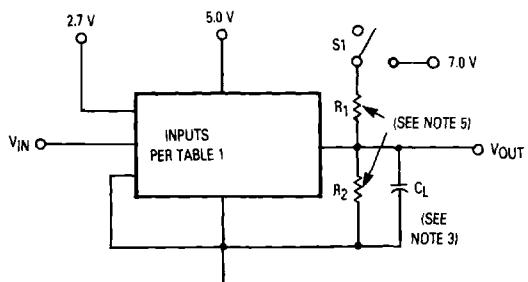
FUNCTIONAL DESCRIPTION

The 'F534 consists of eight edge-triggered flip-flops with individual D-type inputs and 3-state true outputs. The buffered clock and buffered Output Enable are common to all flip-flops. The eight flip-flops will store the state of their individual D inputs that meet the setup and hold times requirements on the LOW-to-HIGH Clock (CP) transition.

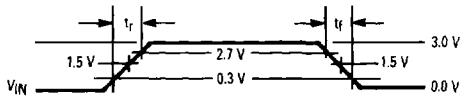
With the Output Enable (QE) LOW, the contents of the eight flip-flops are available at the outputs. When the QE is HIGH, the outputs go to the high impedance state. Operation of the QE input does not affect the state of the flip-flops.

AC TEST CIRCUIT

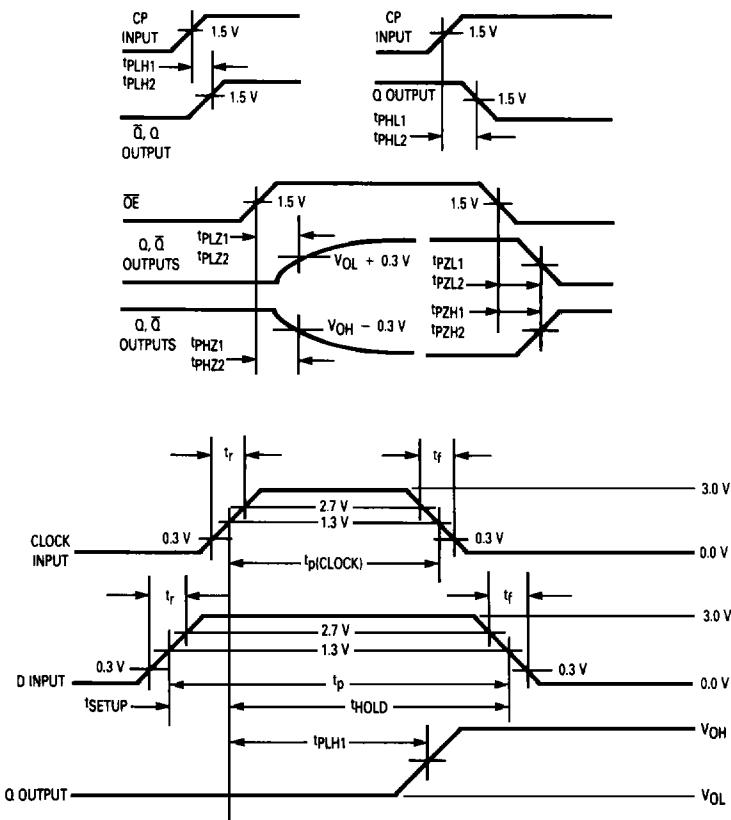
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Test Type	S1
t _{PLH}	open
t _{PHL}	open
t _{PHZ}	open
t _{PZH}	open
t _{PLZ}	closed
t _{PZL}	closed



WAVEFORMS



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NOTES:

1. $t_r = t_f \leq 2.5\text{ ns}$.
2. PRR as in table 1, duty cycle $50 \pm 15\%$.
3. When testing f_{MAX}, the output frequency shall be 1/2 the input frequency.

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Symbol	Parameter	Limits						Units	Test Condition (Unless Otherwise Specified)		
		+ 25°C		+ 125°C		- 55°C					
		Subgroup 1		Subgroup 2		Subgroup 3					
		Min	Max	Min	Max	Min	Max				
V _{OH}	Logical "1" Output Voltage	2.5		2.5		2.5		V	V _{CC} = 4.5 V, I _{OH} = - 1.0 mA, V _{I_L} = 0.8 V (all inputs), CP = (See Note 6).		
V _{OL}	Logical "0" Output Voltage		0.5		0.5		0.5	V	V _{CC} = 4.5 V, I _{OL} = 20 mA, V _{I_H} = 2.0 V (all inputs), CP = (See Note 6), OE = 0.8 V.		
V _{IC}	Input Clamping Voltage		- 1.2					V	V _{CC} = 4.5 V, I _{IN} = - 18 mA, other inputs are open.		
I _{IH}	Logical "1" Input Current		20		20		20	μA	V _{CC} = 5.5 V, V _{I_H} = 2.7 V (all inputs).		
I _{IHH}	Logical "1" Input Current		100		100		100	μA	V _{CC} = 5.5 V, V _{I_{HH}} = 7.0 V (all inputs).		
I _{OD}	Diode Current	35		35		35		mA	V _{CC} = 4.5 V, V _{IN} = 5.5 V (all inputs), OE = 0 V, CP = (See Note 6), V _{OUT} = 2.5 V.		
I _{IL}	Logical "0" Input Current	- 0.03	- 0.6	- 0.03	- 0.6	- 0.03	- 0.6	mA	V _{CC} = 5.5 V, V _{IN} = 0.5 V (all inputs).		
I _{OS}	Output Short Circuit Current	- 60	- 150	- 60	- 150	- 60	- 150	mA	V _{CC} = 5.5 V, V _{IN} = 0 V (all inputs), V _{OUT} = 0 V, CP = (See Note 6).		
I _{IOZH}	Output Off Current High		50		50		50	μA	V _{CC} = 5.5 V, V _{IN} = 2.7 V (all inputs), V _{OUT} = 2.7 V, OE = 2.0 V, CP = (See Note 6).		
I _{IOZL}	Output Off Current Low		- 50		- 50		- 50	μA	V _{CC} = 5.5 V, V _{IN} = 0 V (all inputs), V _{OUT} = 0.5 V, OE = 2.0 V, CP = (See Note 6).		
I _{CCZ}	Power Supply Current Off		86		86		86	mA	V _{CC} = 5.5 V, V _{IN} = 4.5 V (all inputs).		
V _{I_H}	Logical "1" Input Voltage	2.0		2.0		2.0		V	V _{CC} = 4.5 V.		
V _{I_L}	Logical "0" Input Voltage		0.8		0.8		0.8	V	V _{CC} = 4.5 V.		
	Functional Tests	Subgroup 7		Subgroup 8A		Subgroup 8B			per Truth Table with V _{CC} = 4.5 V, (Repeat at) V _{CC} = 5.5 V, V _{INL} = 0.5 V, and V _{INH} = 2.5 V.		

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Symbol	Parameter	Limits						Units	Test Condition (Unless Otherwise Specified)		
		+ 25°C		+ 125°C		- 55°C					
		Subgroup 9		Subgroup 10		Subgroup 11					
		Min	Max	Min	Max	Min	Max				
t_{PHL2}	Propagation Delay /Data-Output CP to \bar{Q}_n	4.0	8.5	4.0	11	4.0	11	ns	$V_{CC} = 5.0 \text{ V}, C_L = 50 \text{ pF}, R_1 = R_2 = 499 \Omega.$		
t_{PLH2}	Propagation Delay /Data-Output CP to \bar{Q}_n	4.0	8.5	4.0	10.5	4.0	10.5	ns	$V_{CC} = 5.0 \text{ V}, C_L = 50 \text{ pF}, R_1 = R_2 = 499 \Omega.$		
t_{PLZ2}	Propagation Delay /Data-Output OE to \bar{Q}_n	1.5	5.5	1.5	7.5	1.5	7.5	ns	$V_{CC} = 5.0 \text{ V}, C_L = 50 \text{ pF}, R_1 = R_2 = 499 \Omega.$		
t_{PHZ2}	Propagation Delay /Data-Output OE to \bar{Q}_n	1.5	7.0	1.5	8.0	1.5	8.0	ns	$V_{CC} = 5.0 \text{ V}, C_L = 50 \text{ pF}, R_1 = R_2 = 499 \Omega.$		
t_{PZL2}	Propagation Delay /Data-Output OE to \bar{Q}_n	2.0	7.5	2.0	10	2.0	10	ns	$V_{CC} = 5.0 \text{ V}, C_L = 50 \text{ pF}, R_1 = R_2 = 499 \Omega.$		
t_{PZH2}	Propagation Delay /Data-Output OE to \bar{Q}_n	2.0	11.5	2.0	14	2.0	14	ns	$V_{CC} = 5.0 \text{ V}, C_L = 50 \text{ pF}, R_1 = R_2 = 499 \Omega.$		
f_{MAX}	Maximum Clock Frequency	80		60		60		MHz	$V_{CC} = 5.0 \text{ V}, C_L = 50 \text{ pF}, (\text{See Note 7}).$		
$t_s(H)$	Setup Time, HIGH D_n to CP	2.5		2.5		2.5		ns	$V_{CC} = 5.0 \text{ V}, C_L = 50 \text{ pF}, (\text{See Note 7}).$		
$t_s(L)$	Setup Time, LOW D_n to CP	2.0		2.0		2.0		ns	$V_{CC} = 5.0 \text{ V}, C_L = 50 \text{ pF}, (\text{See Note 7}).$		
$t_h(H)$	Hold Time, HIGH D_n to CP	2.0		2.0		2.0		ns	$V_{CC} = 5.0 \text{ V}, C_L = 50 \text{ pF}, (\text{See Note 7}).$		
$t_h(L)$	Hold Time, LOW D_n to CP	2.5		2.5		2.5		ns	$V_{CC} = 5.0 \text{ V}, C_L = 50 \text{ pF}, (\text{See Note 7}).$		

NOTES:

1. V_{IN} = Input pulse has the following characteristics: $t_r = t_f \leq 2.5 \text{ ns}$, $PRR \leq 1.0 \text{ MHz}$.
2. Terminal conditions (pins not designated may be high $\geq 2.0 \text{ V}$, low $\leq 0.8 \text{ V}$, or open).
3. $C_L = 50 \text{ pF} \pm 10\%$ including scope probe, wiring and stray capacitance, without package in test fixture.
4. Voltage measurements are to be made with respect to network ground terminal.
5. $R_1 = R_2 = 499 \Omega \pm 5.0\%$.
6. Apply all voltages, then apply 3.0 V, 0 V, 3.0 V to CP, then make measurement.
7. This is for information only, no test required.
8. f_{MAX} minimum limit specified is the frequency of the input pulse. The output frequency shall be 1:2 the input frequency.